

RDS010

900MHz Direct Digital Frequency Synthesizer (DDFS)

REV-DATE PA1-2412 FILE DS_0044PA1-2412





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900MHz Direct Digital Frequency Synthesizer (DDFS)

Features

- 900MHz Clock Frequency
- ♦ 0 to 450MHz Tuning Bandwidth
- ♦ 32Bit Frequency Resolution
- Dual Frequency Control Register
- ♦ 12Bit Phase Modulation
- Dual Phase Control Register
- ♦ Latency of 23 Clock Cycles
- Integrated 12Bit DAC
- ♦ 60dBc SFDR
- ♦ 0dBm Output Power
- ♦ 3.3V Power Supply
- ♦ 3.5W Power Dissipation
- CMOS compatible Data Inputs
- Internally Terminated Outputs
- 88 Pin QFP Hermetic Ceramic Package

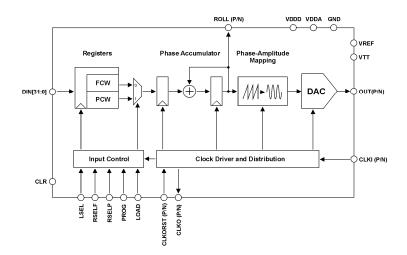


Figure 1 - Functional Block Diagram

Product Description

The RDS010 is a high performance SiGe direct digital frequency synthesizer (DDS) with a clock frequency of 900MHz. The RDS010 has been optimized for ultra-high speed applications, achieving better than 60dBc of spurious output

at 900MHz reference clock frequency. On-chip DAC outputs are internally terminated with 50Ω resistors for better dynamic performance.

Ordering information

PART NUMBER	DESCRIPTION	CAUTION
RDS010-QP	900MHz DDFS, QFP Package	DEVICE SUSCEPTIBLE TO
RDS010-DI	900MHz 32Bit FCW DDFS, DIE	DAMAGE BY ELECTROSTATIC DISCHARGE (ESD)
EVRDS010-QP	RDS010-QP Evaluation Board	DISCHARGE (ESD)



Absolute Maximum Ratings

Supply Voltages Between GNDs -0.3 to +0.3 V Between VDDs -0.3 to +0.3 V
VDDs to GND1 V to +4 V
RF Input Voltages
CLKIP, CLKIN to GND1 to +4 V CLKORSTP, CLKORSTN to GND1 to +4 V
DC Analog Input Voltages
VTT to GNDV
Digital Input Voltages
CLR to GND
LSEL to GNDV
RSELF, RSELP to GNDV
PROG to GND V LOAD to GND V
Output Termination Voltages
OUTP, OUTN to GND
CLKOP, CLKON to GND
Temperature
Case Temperature15 to +85 °C Junction Temperature+100 °C
Lead, Soldering (10 Seconds)+220 °C Storage+40 to 125 °C



DC Electrical Specification

Test Conditions (see notes for specific conditions): Room Temperature; VDD = 3.3V; VREF = 1.3V; VTT = 1.3V; Clock: 900MHz, 0.6Vpp Differential; Outputs Terminated Into 50 Ω to VDD.

	PARAMETER	SYMBOL	BOL CONDITIONS, NOTE		TYP	MAX	UNITS	
1.0	TEMPERATURE DRIFT				•			
1.1	Warm-up Time		After Power-up			30	S	
2.0	CLOCK INPUT (CLKIP, CL	PUT (CLKIP, CLKIN)						
2.1	Input Resistance	R _{CLKI}	Resistance (CLKI P/N) to VTT	45	50	55	Ω	
2.2	Input Capacitance	C _{CLKI}			1.5		pF	
3.0	HIGH SPEED DIGITAL INPUT (CLKORSTP, CLKORSTN)							
3.1	Input Resistance	R _{HDIN}	Resistance to VTT		50		Ω	
3.2	Input Capacitance	C_{HDIN}			1.5		pF	
4.0	DIGITAL INPUTS (DI<0:31>	, CLR, EN	I, PROG, LSEL, RSELF, RSELP, LOAD)				
4.1	Input Capacitance	C_{DIN}			1.5		pF	
5.0	ANALOG OUTPUTS (OUTF	P, OUTN)						
5.1	Output Voltage Swing	V_{FSD}	Differential, Terminated Into 50Ω to VCC=3.3V on Each Output		630		mVpp	
5.2	Output Voltage Swing	V _{FSS}	Single Ended, Terminated Into 50Ω to VCC=3.3V		315		mVpp	
5.3	Output Voltage Range	V _{FSRS}	Single Ended, Terminated Into 50Ω to VCC=3.3V (MIN=000h, MAX=FFFh)	2.9		3.3	V	
5.4	Output Current	I _{OUT}	Terminated Into 50Ω to VCC=3.3V		6		mA	
6.0	CLOCK OUTPUT (CLKOP, CLKON)							
6.1	Common Mode	$V_{CM,CKO}$	Differential LVPECL		2		V	
6.2	Differential Voltage	$V_{DF,CKO}$	Differential LVPECL	200		800	mV	
7.0	DIGITAL OUTPUT (ROLLP, ROLLN)							
7.1	Common Mode	$V_{CM,RR}$	Differential LVPECL		2		V	
7.2	Differential Voltage	$V_{DF,RR}$	Differential LVPECL	200		800	mV	
8.0	REFERENCE (VREF)							
8.1	Input Resistance	R_{VREF}					Ω	
9.0	POWER SUPPLY REQUIREMENTS							
9.1	Positive Current, Analog	IDDA					mΑ	
9.2	Positive Current, Digital	IDDD					mΑ	
9.3	Power Dissipation	Р			3.5		W	

AC Electrical Specification

Test Conditions (see notes for specific conditions): Room Temperature; VDD = 3.3V; VREF = 1.3V; VTT = 1.3V; Clock: 900MHz, 0.6Vpp Differential; Outputs Terminated Into 50 Ω to VDD.

	PARAMETER	SYMBOL	CONDITIONS, NOTE	MIN	TYP	MAX	UNITS
10.0	DYNAMIC PERFORMANCE						
10.1	Spurious Free Dynamic	SFDR1	$F_{clk} = 900MHz$, $F_{out} = 56MHz$		72		dBc
10.2		SFDR2	$F_{clk} = 900MHz$, $F_{out} = 225MHz$		65		dBc
10.3	Range	SFDR3	$F_{clk} = 900MHz$, $F_{out} = 300MHz$		62		dBc
10.4	Clock Feedthrough	FD	Spurs at F _{clk} = 900MHz				dBc
10.5	Output Flatness	ATT	Attenuation at F _{out} = 400MHz				dB
10.6		PN1	F _{out} = 250MHz, 1kHz Offset		-140		dBc/Hz
10.7	Phase Noise	PN2	F _{out} = 250MHz, 10kHz Offset		-150		dBc/Hz
10.8		PN3	F _{out} = 250MHz, 100kHz Offset		-152		dBc/Hz



Operating Conditions

	PARAMETER	SYMBOL	CONDITIONS, NOTE	MIN	TYP	MAX	UNITS
11.0	CLOCK INPUTS (CLKIP, CLK	IN)					
11.1	Amplitude	$V_{DF,CLKI}$	Differential LVPECL or Sinusoidal	200		800	mV
11.2	Common Mode Voltage	V _{CM,CLKI}	Differential LVPECL or Sinusoidal	1.5	2	3	V
11.3	Maximum Frequency	F _{MAX,CLKI}		900			MHz
11.4	Minimum Frequency	F _{MIN,CLKI}				1	MHz
12.0	HIGH SPEED DIGITAL INPUT	(CLKORS	STP, CLKORSTN)				
12.1	Amplitude	$V_{DF,CKOR}$	Differential LVPECL	200		800	mV
12.2	Common Mode Voltage	$V_{CM,CKOR}$	Differential LVPECL	1.7	2	2.8	V
13.0	DIGITAL INPUTS (DI<0:31>, C	CLR, EN, F	ROG, LSEL, RSELF, RSELP, LOA	D)			
131	Input High Voltage	$V_{IH,DIN}$		1.7			V
13.2	Input Low Voltage	$V_{IL,DIN}$				1.2	V
14.0	TIMMING CHARACTERISTICS	S					
14.1	DIN to PROG Setup	t _{STDTPG}		400			ps
14.2	DIN to PROG Hold	t _{HDDTPG}		250			ps
14.3	RSEL, LSEL to PROG Setup			350			ps
14.4	RSEL, LSEL to PROG Hold	t _{HDCTPG}		400			ps
14.5	LOAD to CLKO Setup	t _{STLDCK}		700			ps
14.6	LOAD to CLKO Hold	t _{HDLDCK}		0			ps
14.7	RSEL, LSEL to LOAD Setup	t _{STCTLD}		210			ps
14.8	RSEL, LSEL to LOAD Hold	t _{HDCTLD}		150			ps
14.9	CLKORST to CLKI Setup	t _{STCRCK}		50			ps
14.10	CLKORST to CLKI Hold	t _{HDCRCK}		400			ps
14.11	Load to Output Latency	LTC		23		23	CLKI
15.0	TERMINATION VOLTAGE (VT	ΓT)					
15.1	Reference Voltage	V_{TT}	Termination Voltage for CLKI		1.3		V
16.0	REFERENCE (VREF)						
16.1	Reference Voltage	V_{REF}			1.3		V
17.0	POWER SUPPLY REQUIREM	ENTS					
17.1	Supply Voltage, Analog	VDDA		3.1	3.3	3.5	V
17.2	Supply Voltage, Digital	VDDD		3.1	3.3	3.5	V
18.0	OPERATING TEMPERATURE						
18.1	Case Temperature	Tc	Measured at Bottom Plate	-15		85	°C
18.2	Junction Temperature	Tj				120	°C



Pin Description

P/I/O	PIN	NUM.	NAME	FUNCTION
Р	1, 2, 6, 7, 52, 54, 55	7	VDD	Digital VDD Power Supply
Р	71, 72, 73, 74, 75	5	VDDA	Analog VDD Power Supply
Р	58, 59, 60, 61, 62, 63, 64, 68, 69, 70, 77, 78, 79, 84, 85, 86, 87, 88, bottom plate	18	GND	Ground
l	4	1	VTT	Input Clock Termination Voltage
I	76	1	VREF	DAC Core Reference Voltage
ı	16, 17, 18, 19, 20, 21, 22, 23, 24, 25, 26, 27, 28, 29, 31, 32, 33, 34, 35, 39, 40, 41, 42, 43, 44, 45, 46, 47, 48, 49, 50, 51	32	DI<0:31>	DI<0:31> is the 32Bit input Data. MSB is Bit 31 FCW uses DI<0:31>, PCW uses DI<0:11>
ı	13	1	LSEL	Frequency / Phase Selection: 0 - Frequency 1 - Phase
I	14	1	RSELF	Frequency Register Selection: 0 - Register 1 1 - Register 2
I	15	1	RSELP	Phase Register Selection: 0 - Register 1 1 - Register 2
ı	30	1	PROG	Program Control Signal. Active High
ı	36	1	LOAD	Load The NCO Accumulator. Synchronous with CLKO
ı	10	1	CLR	NCO Clear Signal. Active High
I	9	1	CLKORSTP	High Speed Output Clock Reset
	8	1	CLKORSTN	High Speed Output Clock Reset
I	5	1	CLKIP	CLKIP / CLKIN Is Differential Input Clock
I	3	1	CLKIN	CERT / CERTIN IS DIFFERENTIAL INPUT CIOCK
1	53	1	EN	Device Enable: 0 - Disable 1 - Enable
0	11	1	ROLLP	ROLLP / ROLLN Is Differential NCO Accumulator
0	12	1	ROLLN	Overflow
0	38	1	CLKOP	CLKOP / CLKON Is Differential Output Clock (Operating
0	37	1	CLKON	Clock Divided by 4)
0	66	1	OUTP	OUTP / OUTN Is Differential Output
0	65	1	OUTN	OOTF / OOTN IS Dilleteritial Output
RES	82	1	RESP	Reserved – connect to VDD
RES	80, 81, 83	3	RESN	Reserved – connect to GND
RES	56, 57, 67	3	RES	Reserved – No connect

All digital inputs are CMOS compatible, except: CLKi(P/N) and CLKORST(P/N), which are LVPECL. The outputs CLKO(P/N) and ROLL(P/N) are also LVPECL.



Pin Layout (TOP view)

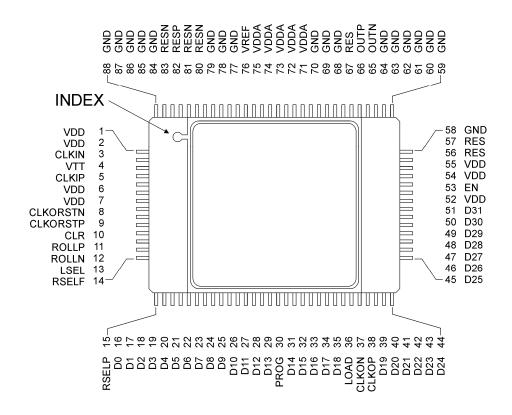


Figure 2 - RDS010-QP pinout (top view).



Theory of Operation

The RDS010 is a single chip direct digital frequency synthesizer with a numerically controlled oscillator (NCO) and a digital to analog converter (DAC). The NCO can be divided into three blocks: input, accumulator and phase to amplitude mapping. The input interfaces the NCO with the exterior. It controls the programming, frequency and phase, of the DDFS. After a new frequency or phase is programmed, the accumulator generates a ramp that sweeps through the full range of possible phase values with the desired frequency. Those values address the phase to amplitude mapping to determine a digitized sine amplitude value. The DAC is then employed to convert the digital data to an analog waveform.

The DAC employs 4Bit segmentation and 8Bit binaryweighted codes for high-speed and best dynamic performance. The 12Bit NCO output is latched by master-slave flip-flops immediately after the buffers to reduce the data skew. The 4 MSB data bits are decoded into thermometer code by a two-stage decoding block, and the 8 LSB data bits are transported through the delay equalizer block. The digital data are then synchronized again by a second master-slave flip-flop to reduce the switching glitch. The decoded 4 MSB data drive 15 identical current switches, and the 8 LSB data drive 8 current switches. The output nodes from the LSB current switches are connected to the analog output through an R-2R ladder to generate the binary output. The DAC of RDS010 provides output terminated at 50Ω . For static linearity performance, randomized current source resistors and switching sequence are implemented. VREF pin can be used to override the internal reference with an accurate, temperaturecompensated external voltage reference.

Programming the RDS010

Programming the RDS010 is done in two steps. The first step writes the 32bit input data to the selected control register. The second step loads the contents of the selected control register into the accumulator. During the first step the, which is asynchronous, the control register to be written is selected using LSEL (frequency or phase control register) and RSELF/RSELP, which select the register 0 or 1. The input data is then written to the select register during the rising edge of PROG. The second step is synchronous with the operating clock and is done by

sampling LOAD with CLKO. LSEL is used to indicate if a frequency or phase control word is going to be loaded into the accumulator. When loading a new frequency control word (FCW) into the accumulator, RSELF indicate which frequency control register contains the desired FCW. RSELP can assume any state. In the case a new phase control word (PCW) is going to be loaded, RSELP indicate which register to use and RSELF should indicate which frequency control register contains the current FCW being used in the accumulator.



Timming Diagrams

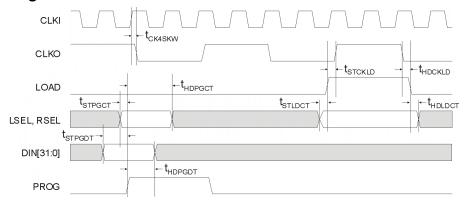


Figure 3 - Input register programming and NCO load

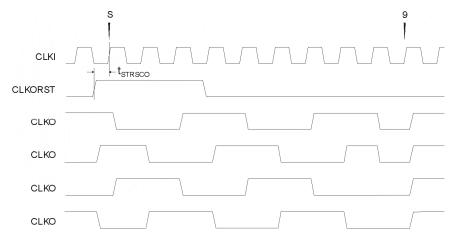


Figure 4 – Output clock reset

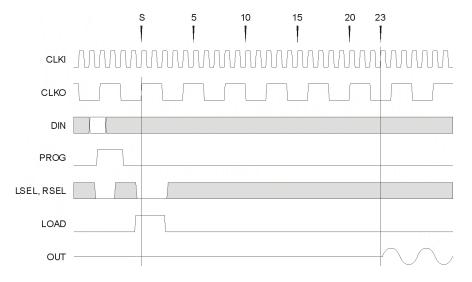


Figure 5 - Latency



Typical Operating Circuit

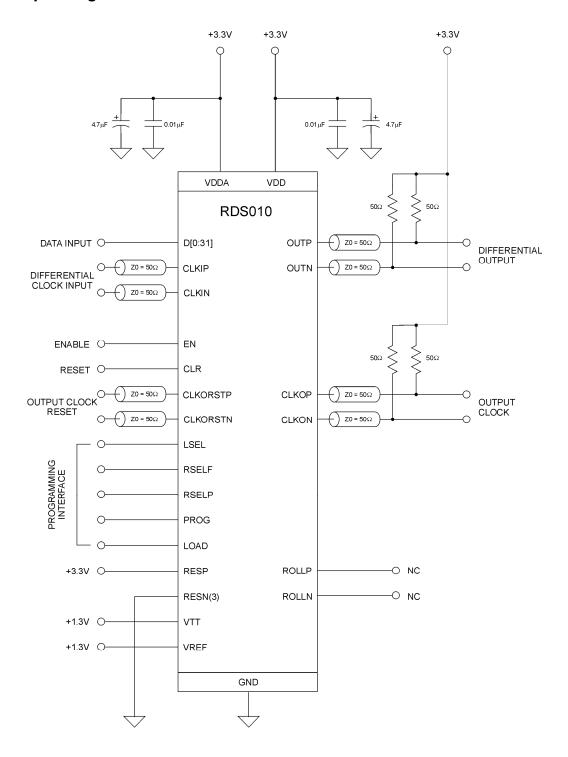


Figure 6 - RDS010-QP typical operating circuit.



Typical Performance

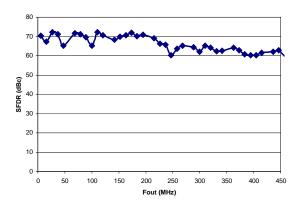


Figure 7 - SFDR x Fout with Fclk=900MHz

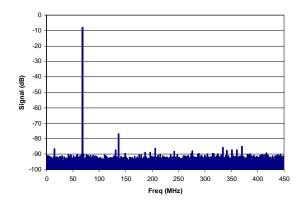


Figure 8 - Spectrum with FcIk=900MHz, Fout=68MHz

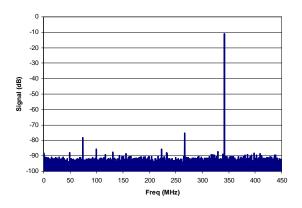


Figure 9 – Spectrum with Fclk=900MHz, Fout=341MHz



Package Information

The package is a 88 lead ceramic Quad Flat Pack (QFP) with a heat sink slug on the package's bottom. The leads are trimmed to 0.045 inch (1.15mm) length

(from the package edge). The thermal impedance (junction to base) is approximately 3.5 °C/W.

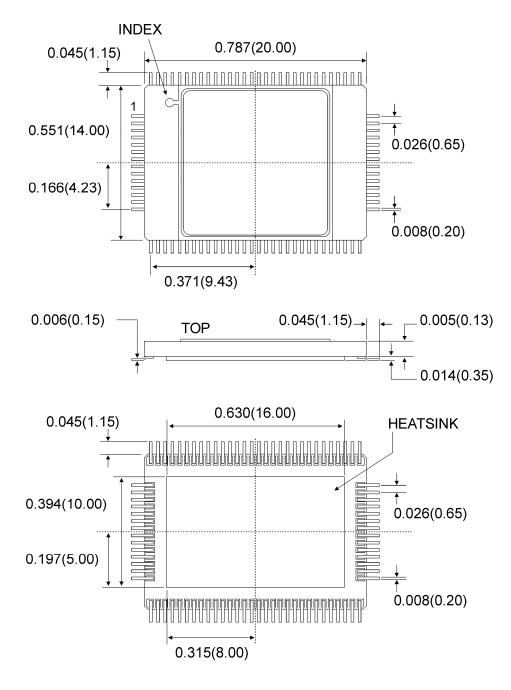


Figure 10 - RDS010-QP package, dimensions shown in inches (mm).